

Search Notes

Application/Control No.

10/066,363

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

FINSTER ET AL.

Art Unit

2623

SEARCHED

Class	Subclass	Date	Examiner
725	38-61	7/18/2006	A.S
709	217-224	7/18/2006	A.S
709	246	7/18/2006	A.S

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner